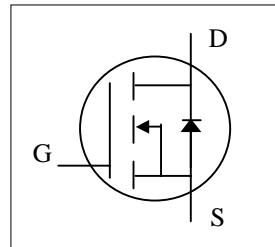
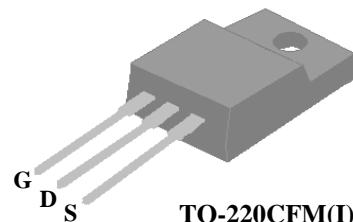




- ▼ 100% R<sub>g</sub> & UIS Test
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free



BV <sub>DSS</sub>	650V
R <sub>DS(ON)</sub>	0.47Ω
I <sub>D</sub> <sup>3</sup>	14A



## Description

AP65WN470 series are from the innovated design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-220CFM package is widely preferred for all commercial-industrial through hole applications. The mold compound provides a high isolation voltage capability and low thermal resistance between the tab and the external heat-sink.

## Absolute Maximum Ratings@T<sub>j</sub>=25°C(unless otherwise specified)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	650	V
V <sub>GS</sub>	Gate-Source Voltage	±30	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Drain Current, V <sub>GS</sub> @ 10V <sup>3</sup>	14	A
I <sub>DM</sub>	Pulsed Drain Current <sup>1</sup>	56	A
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation	41.6	W
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation	1.92	W
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>4</sup>	125	mJ
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
R <sub>thj-c</sub>	Maximum Thermal Resistance, Junction-case	3	°C/W
R <sub>thj-a</sub>	Maximum Thermal Resistance, Junction-ambient	65	°C/W



## Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=250\mu\text{A}$	650	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_{\text{D}}=7\text{A}$	-	-	0.47	$\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=250\mu\text{A}$	2	-	4	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=20\text{V}$ , $I_{\text{D}}=7\text{A}$	-	22	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=520\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	100	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 30\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 1$	$\mu\text{A}$
$Q_g$	Total Gate Charge	$I_{\text{D}}=7\text{A}$	-	68	108.8	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=520\text{V}$	-	13	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	24	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=325\text{V}$	-	64	-	ns
$t_r$	Rise Time	$I_{\text{D}}=7\text{A}$	-	57	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_{\text{G}}=50\Omega$	-	420	-	ns
$t_f$	Fall Time	$V_{\text{GS}}=10\text{V}$	-	92	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2720	4352	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	120	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	10	-	pF
$R_g$	Gate Resistance	f=1.0MHz	-	3.2	6.4	$\Omega$

### Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=7\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.5	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_{\text{S}}=7\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	450	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	dl/dt=100A/ $\mu\text{s}$	-	2.7	-	$\mu\text{C}$

### Notes:

1. Pulse width limited by max. junction temperature.
2. Pulse test
3. Ensure that the junction temperature does not exceed  $T_{\text{jmax}}$ .
4. Starting  $T_j=25^\circ\text{C}$ ,  $V_{\text{DD}}=50\text{V}$ ,  $L=10\text{mH}$ ,  $R_{\text{G}}=25\Omega$

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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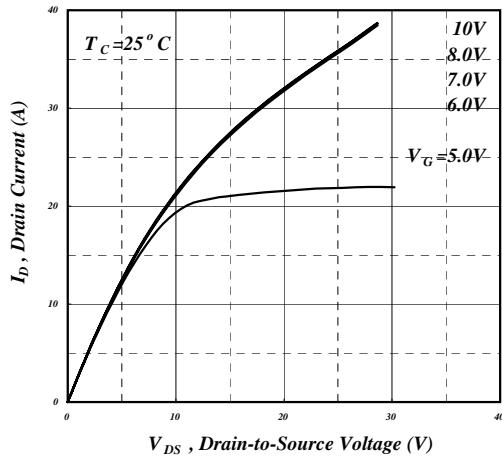


Fig 1. Typical Output Characteristics

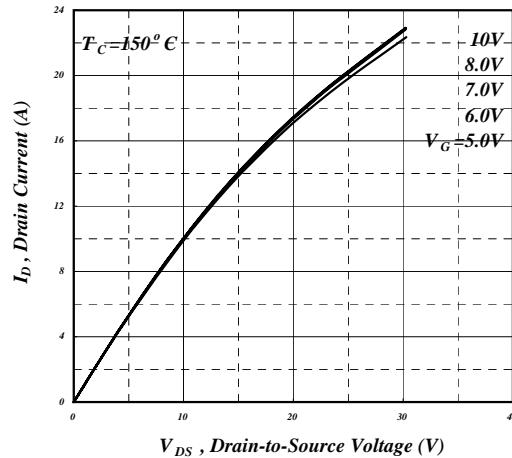


Fig 2. Typical Output Characteristics

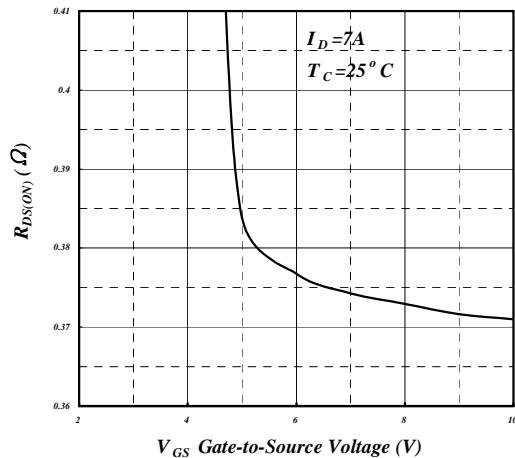


Fig 3. On-Resistance v.s. Gate Voltage

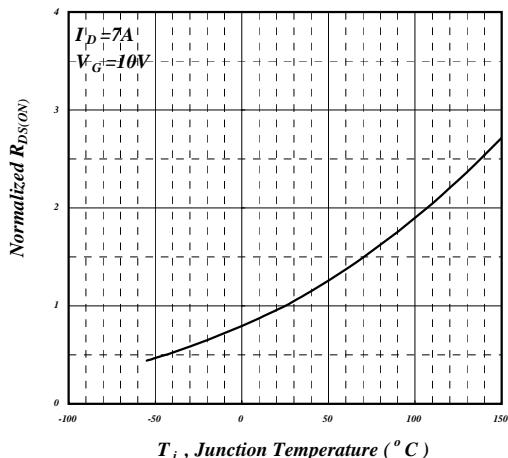


Fig 4. Normalized On-Resistance v.s. Junction Temperature

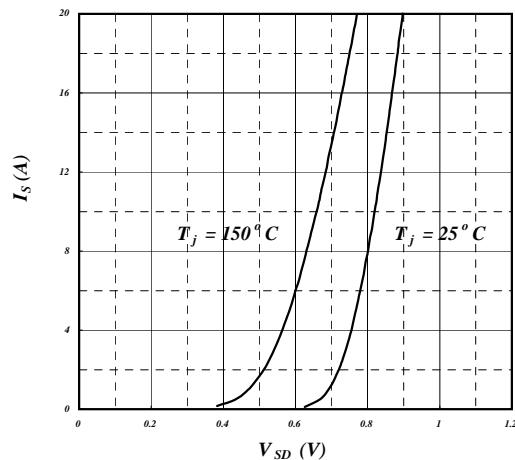


Fig 5. Forward Characteristic of Reverse Diode

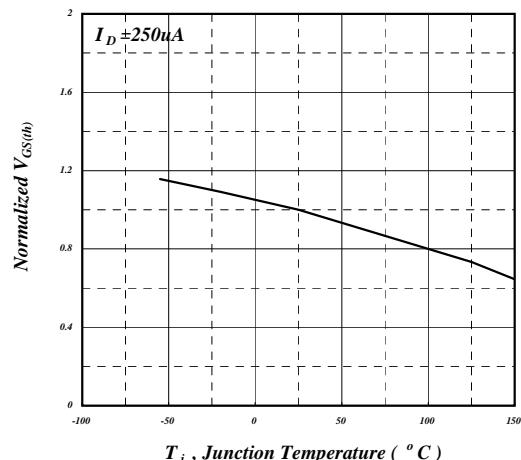
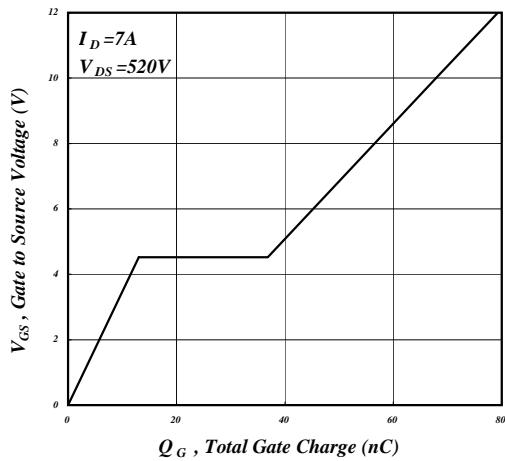
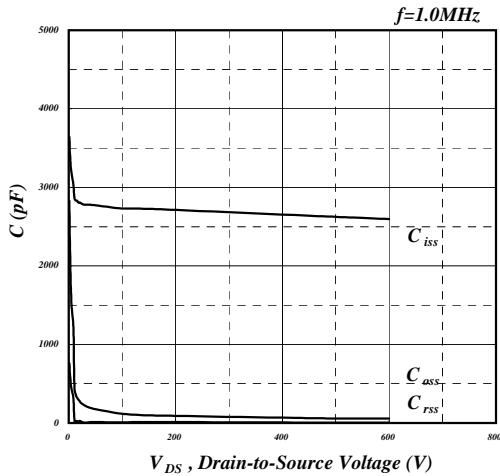


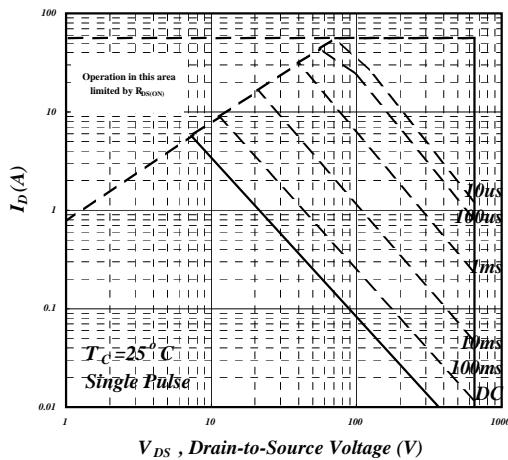
Fig 6. Gate Threshold Voltage v.s. Junction Temperature



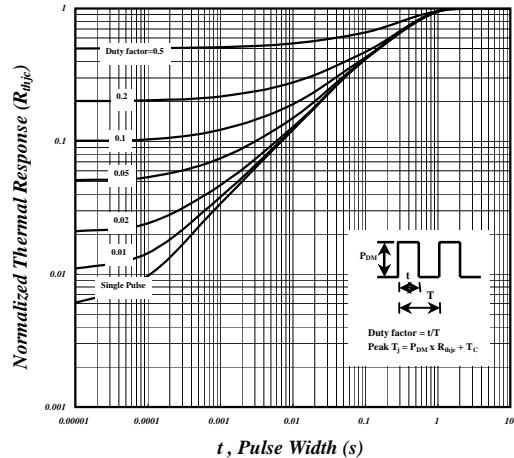
**Fig 7. Gate Charge Characteristics**



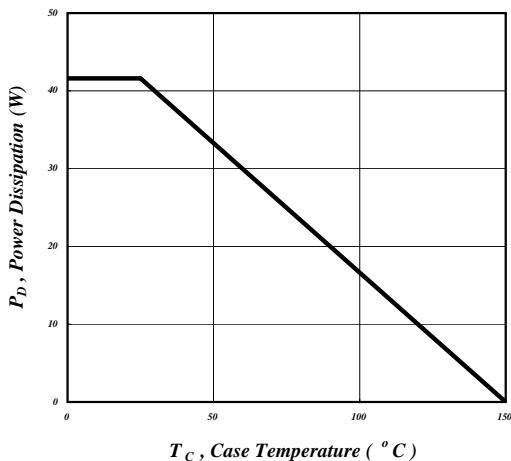
**Fig 8. Typical Capacitance Characteristics**



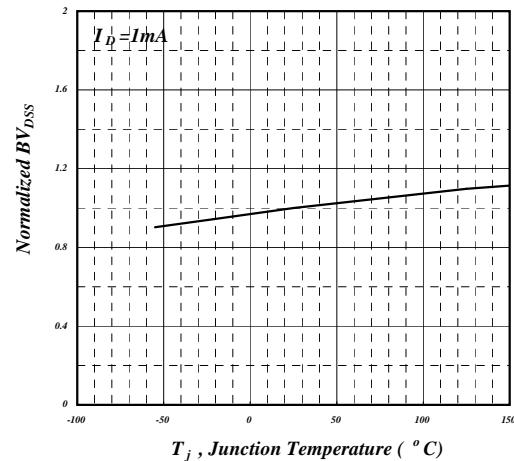
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Total Power Dissipation**



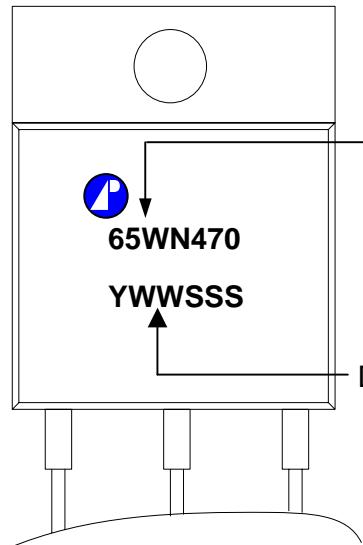
**Fig 12. Normalized  $BV_{DS}$  v.s. Junction Temperature**



**AP65WN470I**

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## MARKING INFORMATION



Part Number

Date Code (YWWSSS)

Y : Last Digit Of The Year

WW : Week

SSS : Sequence